

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 371 of PCT/KR2004/00374
Applicant : Gyu Chul YI et al.
Filed : Herewith
TC/A.U. : Not Yet Assigned
Examiner : Not Yet Assigned

Docket No. : 1751-391
Customer No. : 06449
Confirmation No. : Not Yet Assigned

INFORMATION DISCLOSURE STATEMENT

Director of the United States Patent
and Trademark Office
P.O. Box 1450
Alexandria, Virginia 22313-1450

Dear Sir:

Under the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant submits herewith a copy of the International Search Report and information that the Office may wish to consider in examination of the subject application. Materials submitted for consideration are listed on the attached form PTO-1449.

Respectfully submitted,

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Enclosure(s): International Search Report
(5) Cited References

INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Complete if Known 10/558899	
				Application Number	371 of PCT/KR2004/000374
				Filing Date	Herewith
				First Named Inventor	Gyu Chul Yi et al.
				Group Art Unit	
				Examiner Name	
				Confirmation No.	
Sheet	1	of		Attorney Docket Number	1751-391

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code ² (if known)		

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T ⁶
		Office ³ Code	Number ⁴	Kind ⁵ (if known)			
	1	JP	2000-031462	A	CANON INC	01-28-2000	AB
	2	JP	2003-045661	A	FUJI PHOTO FIL CO LTD	02-14-2003	AB
	3	JP	2003-073859	A	NATIONAL INSTITUTE FOR MATERIALS SCIENCE	03-12-2003	AB
	4	KR	10-2003-0085272	A	POSTECH FOUNDATION	11-05-2003	AB
	5	WO	94/00885	A1	ISIS INNOVATION LTD.	01-06-1994	
Examiner Signature						Date Considered	

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¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code.

⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.